

PROCEEDINGS OF SPIE

Terahertz for Military and Security Applications V

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Hong-Liang Cui

Editors

9–10 April 2007

Orlando, Florida, USA

Sponsored and Published by

SPIE—The International Society for Optical Engineering

Volume 6549



**The International Society
for Optical Engineering**

Proceedings of SPIE—The International Society for Optical Engineering, 9780819466716, v. 6549

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Author(s), "Title of Paper," in *Terahertz for Military and Security Applications V*, edited by James O. Jensen, Hong-Liang Cui, Proceedings of SPIE Vol. 6549 (SPIE, Bellingham, WA, 2007) Article CID Number.

ISSN 0277-786X
ISBN 9780819466716

Published by

SPIE—The International Society for Optical Engineering

P.O. Box 10, Bellingham, Washington 98227-0010 USA
Telephone 1 360/676-3290 (Pacific Time) · Fax 1 360/647-1445
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Printed in the United States of America.

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